DON North and	Number 20170020002									
PCN Number:		20170928002 of Carsem Suzhou (CSZ) as additional A					PCN Date: Oct. 2, 2017			
Title: Qualif	es		hou	(CSZ) a	is add	litional Assen	nbly	and Test Site for Select		
Customer Contact: PCN Manager					Dep			ity Services		
Proposed 1 st Ship Date:		Jan 2, 201	.8			Estimated Sample Availability:		Date Provided at Sample request		
Change Type:						-				
Assembly S	te		Design				Wafer Bump Site			
Assembly Pi	ocess			Data	Sheet	t		Wafer Bump Material		
Assembly M	aterials			Part i	numb	er change		Wafer Bump Process		
Mechanical	Specificati	on	\boxtimes	Test:	Site			Wafer Fab Site		
Packing/Shi	oping/Lab	eling		Test	Proce	SS		Wafer Fab Materials		
								Wafer Fab Process		
			P	CN D	etail	S				
Description of (hange:									
Qualification of Carsem Suzhou (CSZ) as additional Assembly and Test Site for Select Devices listed in the "Product Affected" Section. Current assembly sites and Material differences are as follows.										
Assembly S	te Asse	mbly Site Or	igin	Asser	nbly (Country Code		Assembly Site City		
TI Clark		QAB				HL	F	Angeles City, Pampanga		
TI Malaysia		MLA			M	IYS		Kuala Lumpur		
Carsem Suzh	ou	CSZ			С	HN		Jiangsu		
Group 1 Materia		nces:	TI	Malays	sia	Carsem S	uzho	ou .		
Marriat										
Mount compoun	u 42	07768	4	1207768	5	43514	+3			
Group 2 Materia	al Differe	nces:								
		lalaysia	Car	sem Su	ızhou					
Mount compoun	d 420	07768		43514	3					
Wire type		Au		Cu						
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.										
Reason for Cha	nge:									
Continuity of Sup	ply									
Anticipated imp	act on Fo	orm, Fit, Fu	ıncti	on, Qu	ality	or Reliabilit	y (p	ositive / negative):		
None										
Anticipated imp	act on M	aterial Dec	larat	tion						
No Impact to the Material Declaration Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the TI Eco-Info website. There is no impact to the material meeting current regulatory compliance requirements with this PCN change.						owing the production vised reports can be here is no impact to the pliance requirements with				
Anticipated imp	act on Fo	orm, Fit, Fu	ıncti	on, Qu	ality	or Reliabilit	y (p	ositive / negative):		
None										
Changes to pro	duct iden	tification r	esul	ting fro	om th	is PCN:				

Assembly Site		
TI Clark Philippines	Assembly Site Origin (22L)	ASO: QAB
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA
Carsem Suzhou	Assembly Site Origin (22L)	ASO: CSZ

Sample product shipping label (not actual product label)



ASSEMBLY SITE CODES: TI-Clark = I, TI-Malaysia = I, Carsem Suzhou = F

Group 1 Product Affected:

AFE031AIRGZR AFE031AIRGZT TPS53316RGTR TPS53316RGTT	Γ
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Group 2 Product Affected:

THS6212IRHFR	THS6212IRHFT	THS6214IRHFR	THS6214IRHFT
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Group 1 Qualification Report

Qualify RGZ/RGT QFN packages in CARZ

Approve Date 26-Sep-2017

Product Attributes

Attributes	Qual Device: AFE031AIRGZ	Qual Device: TPS53316RGTR				
Assembly Site	CARZ	CARZ				
Package Family	QFN 7.0 X 7.0 (MM)	QFN 3.0 X 3.0 (MM)				
Wafer Fab Supplier	DP1-DM5	MH8				
Wafer Process	50HPA07X3	LBC7				

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: AFE031AIRGZ	Qual Device: TPS53316RGTR
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass
MQ	Manufacturability	(per mfg. Site specification)	Pass	Pass
TC	Temperature Cycle, - 65/150C	500 Cycles	2/154/0	-
YLD	FTY and Bin Summary		Pass	Pass

⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

⁻ Qual Device AFE031AIRGZ is qualified at LEVEL2-260CG

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Group 2 Qualification Report

THS6212IRHFR/THS6214IRHFR Qualification in CARZ

Approve Date 27-Sep-2017

Product Attributes

1 Toddot Attributes					
Attributes	Qual Device: THS6212IRHFR	Qual Device: THS6214IRHFR	QBS Product Reference: THS6212IRHF	QBS Product Reference: THS6214IPWP	QBS Process Reference: TNETD7122APAP
Assembly Site	CARSEM SUZHOU	CARSEM SUZHOU	MLA	MLA	TAI
Package Family	VQFN	QFN	QFN	HTSSOP	HTQFP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	FFAB	FFAB	DFAB	DFAB	DFAB
Wafer Process	BICOM2HV	BICOM2HV	BICOM2XHV	BICOM2XHV	BICOM2XHV

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

-	Test Name /		Qual Device:	Qual Device:	QBS Product	QBS Product	QBS Process
Туре	Condition	Duration	THS6212IRHFR	THS6214IRHFR	Reference: THS6212IRHF	Reference: THS6214IPWP	Reference: TNETD7122APAP
AC	Autoclave 121C	96 Hours	-	-	-	-	3/105/0
ED	Electrical Characterization	Per Datasheet Parameters	-	-	Pass	Pass	Pass
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/230/0	-	-	3/105/0
HBM	ESD - HBM	2000 V	-	-	1/3/0	1/3/0	-
CDM	ESD - CDM	500 V	-	-	1/3/0	-	-
HTOL	Life Test, 125C	967 Hours	-	-	-	-	3/231/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	-	-	-	3/105/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/231/0	-	-	-
LU	Latch-up	(per	-	-	1/6/0	2/12/0	3/15/0

⁻ Qual Devices qualified at LEVEL2-260C: THS6212IRHFR, THS6214IRHFR

		JESD78)					
PD	Physical Dimensions		1/5/0	2/10/0	-	-	-
SD	Solderability	Pb Free	-	3/66/0	-	-	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	-	-	3/105/0
TS	Thermal Shock, -65/150C	500 Cycles	-	-	-	-	3/105/0
UHAST	Unbiased HAST 130C/85%RH	96 Hours	-	3/231/0	-	-	-
WBP	Bond Pull	Wires	1/76/0	3/228/0	-	-	-
WBS	Ball Bond Shear	Wires	1/76/0	3/228/0	-	-	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com